

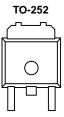
N-Channel 100 V (D-S) MOSFET

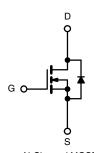
PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)		
	$0.055 \text{ at V}_{GS} = 10 \text{ V}$	25			
100	$0.057 \text{ at V}_{GS} = 4.5 \text{ V}$	25	21nC		
	0.070 at V _{GS} = 2.5 V	18			

FEATURES

- TrenchFET® power MOSFET
- 100 % UIS tested







APPLICATIONS

• Primary side switch

G D S Top View	G S N-Channel MOSFE
Top View	N-Channel MOSFE

ABSOLUTE MAXIMUM RATINGS	(T _A = 25 °C, unless	otherwise note	d)	
PARAMETER	SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	V _{DS}	100	V	
Gate-Source Voltage		V_{GS}		± 20
	T _C = 25 °C		25	
Continuous Drain Current (T. 175 °C)	T _C = 70 °C		20	
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	12 b, c	
	T _A = 70 °C		10 b, c	
Pulsed Drain Current		I _{DM}	75	A
Continuous Courses Dunis Diada Coursest	T _C = 25 °C		50 e	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	6.9 b, c	
Avalanche Current Pulse		I _{AS}	33	
Single Pulse Avalanche Energy	ergy L = 0.1 mH		55	mJ
	T _C = 25 °C		83	
Manian and Danier Disable attack	T _C = 70 °C		58	14/
Maximum Power Dissipation	T _A = 25 °C	P _D	8.3 b, c	W
	T _A = 70 °C		5.8 b, c	
Operating Junction and Storage Temperature F	T _J , T _{stg}	-55 to +175	°C	

THERMAL RESISTANCE RATINGS							
PARAMETER	SYMBOL	TYPICAL	MAXIMUM	UNIT			
Maximum Junction-to-Ambient b, d	t ≤ 10 s	R_{thJA}	15	18	°C/W		
Maximum Junction-to-Case	Steady State	R_{thJC}	1.5	1.8	C/ VV		

Notes

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 50 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 50 A.



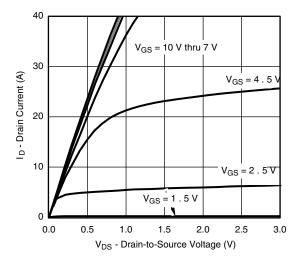
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static			•		•	•
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L 050 A	-	165	-	\//°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA	-	-11	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.8	1.2	1.6	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V V _{DS} = 100 V, V _{GS} = 0 V, T _J = 55 °C	-	-	1 10	μΑ
On-State Drain Current a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	25	-	-	Α
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_{D} = 12 \text{A}$ $V_{GS} = 4.5 \text{ V}, I_{D} = 8 \text{A}$	-	0.055 0.057	0.060 0.062	Ω
Forward Transconductance a	9 _{fs}	V _{DS} = 15 V, I _D = 12 A	-	25	-	S
Dynamic ^b	•					
Input Capacitance	C _{iss}		-	1800	-	pF
Output Capacitance	Coss	$V_{DS} = 12 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	180	-	
Reverse Transfer Capacitance	C _{rss}		-	60	-	
Total Gate Charge	Q_g		-	21	32	nC
Gate-Source Charge	Q_{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 12 \text{ A}$	-	10	-	
Gate-Drain Charge	Q_{gd}		-	9	-	
Gate Resistance	R_g	f = 1 MHz	-	1.5	-	Ω
Turn-On Delay Time	t _{d(on)}		-	10	15	
Rise Time	t _r	$V_{DD} = 50 \text{ V}, R_L = 5 \Omega$	-	10	15	no
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	-	15	25	ns -
Fall Time	t _f		-	10	15	
Drain-Source Body Diode Characteristic	s					
Continuous Source-Drain Diode Current	Is	T _C = 25 °C	-	-	50	Α
Pulse Diode Forward Current ^a	I _{SM}		-	-	40	A
Body Diode Voltage	V _{SD}	I _S = 10 A	-	0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}		-	50	75	ns
Body Diode Reverse Recovery Charge	Q _{rr}	L_ = 10 A di/dt = 100 A/vo T = 25 °C	-	100	150	nC
Reverse Recovery Fall Time	ta	$I_F = 10 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s, T}_J = 25 ^{\circ}\text{C}$	-	38	-	nc
Reverse Recovery Rise Time	t _b			12	-	ns

Note

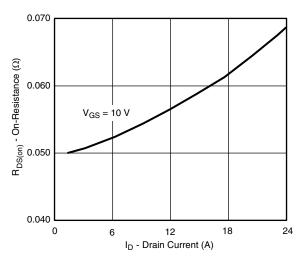
- a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

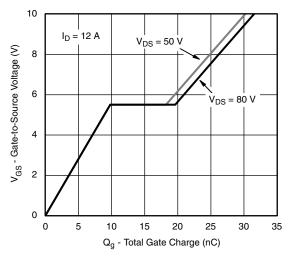




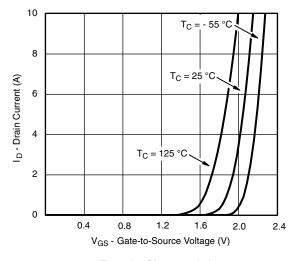




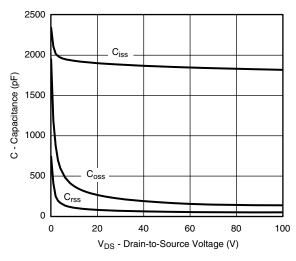
On-Resistance vs. Drain Current



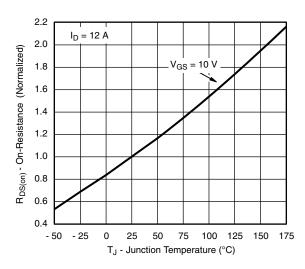
Gate Charge



Transfer Characteristics

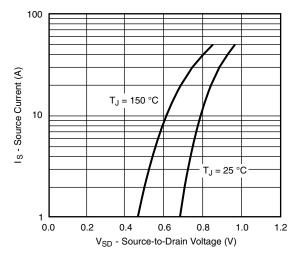


Capacitance

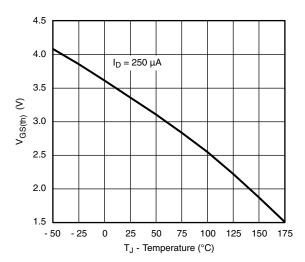


On-Resistance vs. Junction Temperature

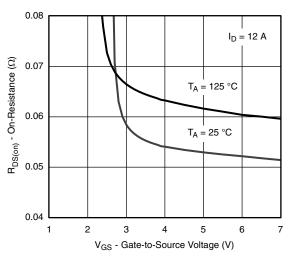




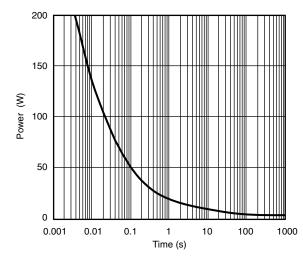
Source-Drain Diode Forward Voltage



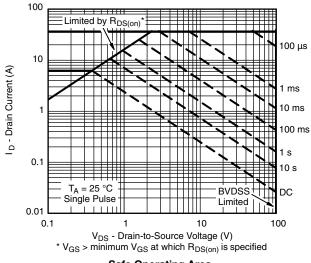
Threshold Voltage



 $R_{DS(on)}$ vs. V_{GS} vs. Temperature

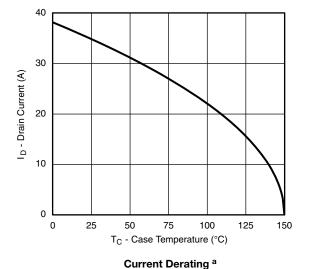


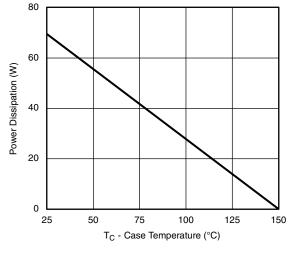
Single Pulse Power, Junction-to-Ambient



Safe Operating Area





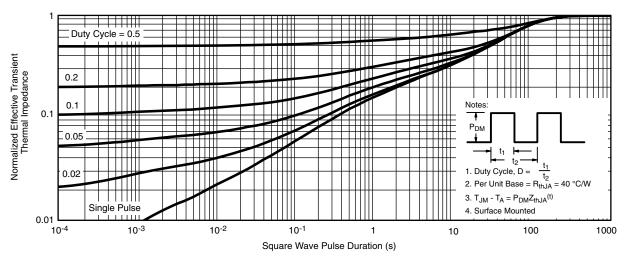


Power Derating

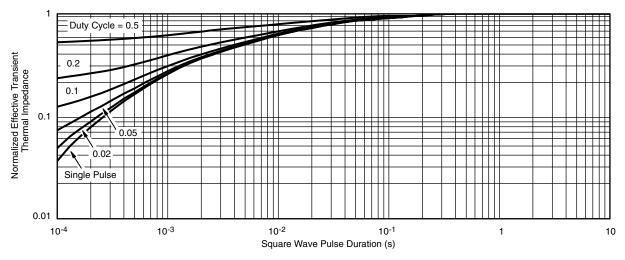
Note

a. The power dissipation P_D is based on T_J (max.) = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





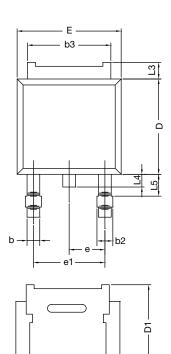
Normalized Thermal Transient Impedance, Junction-to-Ambient

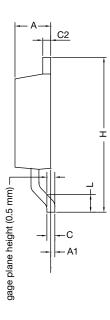


Normalized Thermal Transient Impedance, Junction-to-Case



TO-252AA Case Outline





	MILLIMETERS		INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	2.18	2.38	0.086	0.094	
A1	-	0.127	-	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	4.10	-	0.161	-	
Е	6.35	6.73	0.250	0.265	
E1	4.32	-	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28	BSC	0.090	BSC	
e1	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	-	1.02	-	0.040	
L5	1.01	1.52	0.040	0.060	
FCN: T16-0236-Rev. P. 16-May-16					

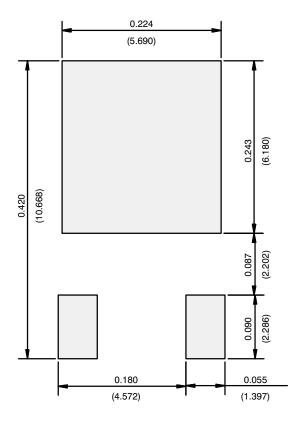
ECN: T16-0236-Rev. P, 16-May-16 DWG: 5347

Notes

• Dimension L3 is for reference only.



RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)



Recommended Minimum Pads Dimensions in Inches/(mm)



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